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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: N. MISE et al
Serial No.: 10/697,326
Filed: October 31, 2003
For: ION CURRENT DENSITY MEASURING METHOD AND
INSTRUMENT, AND SEMICONDUCTOR DEVICE
MANUFACTURING METHOD
Group: 2813
Examiner: C. THOMPSON

RESPONSE TO RESTRICTION REQUIREMENT

Commissioner for Patents
POB 1450
Alexandria, VA 22313-1450

June 16, 2005

Sir:

In reply to the Office Action, dated May 17, 2005, applicants hereby elect Group II, claim 3, drawn to a device, without traverse.

If the Examiner believes that there are any other points which may be clarified or otherwise disposed of either by telephone discussion or by personal interview, the Examiner is invited to contact Applicants' undersigned attorney at the number indicated below.

To the extent necessary, applicants petition for an extension of time under 37 CFR §1.136. Please charge any shortage in the fees due in connection with the filing of this paper, to the Deposit Account of Antonelli, Terry, Stout & Kraus, LLP, Dep. Acct. No. 01-2135 (500.40410VX1), and please credit any excess fees to such deposit account.

Respectfully submitted,
ANTONELLI, TERRY, STOUT & KRAUS, LLP



Gregory E. Montone
Reg. No. 28, 141

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